

Abstract

Nowadays, both analog and digital system blocks are located on the same chip. Most digital design engineers want to verify digital modeled blocks along with analog models for ensuring the functionality of both systems together. This paper describes how analog devices such as DACs, ADCs, LDOs, Filters, and PhotoDiodes can be modeled from user-defined resolved nets, boundary elements, and interconnects. Debugging and visualization of RNM constructs are important during the integration of a complete analog device and during connecting an analog device modeled with SV-RNM language to a digital one.

User-Defined Net-types and Resolved Nets (UDN-UDRN)

User-Defined Nets (UDN) hold the values of voltage, current, and resistance in only one net. New UDN can also support the capacitance value. Figure 1, illustrates that these nets will be resolved by an impedance voltage division. The output voltage and the current are resolved by the following equations.

$$V = \frac{1}{(A+B+C+D)}((B+D)*vin - D*vin_{prev} + (C+D)*vout_{prev})$$

$$I = \frac{1}{A+B+C+D}((B+D)*vin - (D)*vin_{prev} - C*vout_{prev} - C*vout_{prev})$$

where $A = \frac{1}{R_{Load}}$, $B = \frac{1}{R_{Src}}$, $C = \frac{C_{Load}}{dt}$, $D = \frac{C_{Src}}{dt}$

This resolved net can model a Low Pass (LP)/High Pass (HP) filtering effect and a resistance-voltage/capacitance-voltage divider effect. Figure 2, shows which capacitor and resistor need to be set for reaching the desired effect. Figure 3, shows the effect of low and high filtering using this resolved net.

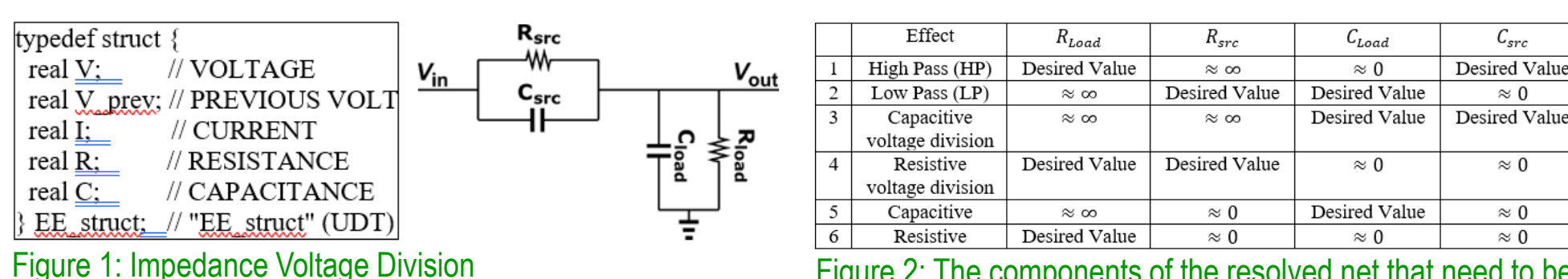


Figure 1: Impedance Voltage Division

Effect	R _{load}	R _{src}	C _{load}	C _{src}
1 High Pass (HP)	Desired Value	∞	∞	∞
2 Low Pass (LP)	∞	Desired Value	∞	∞
3 Capacitive voltage division	∞	∞	Desired Value	∞
4 Resistive voltage division	Desired Value	Desired Value	∞	∞
5 Capacitive	∞	∞	Desired Value	∞
6 Resistive	Desired Value	∞	∞	∞

Figure 2: The components of the resolved net that need to be set

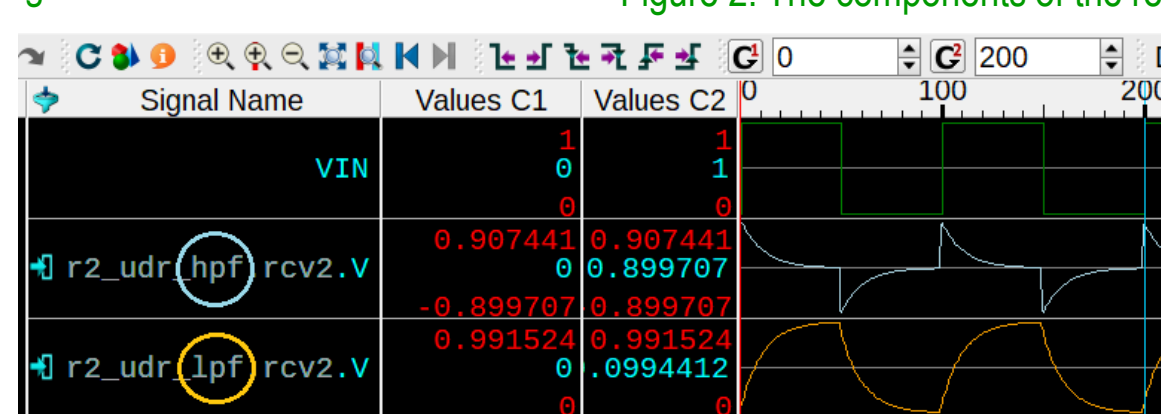


Figure 3: HP & LP filtering effect using resolved net.

Debugging UDN-UDRN

- Understand the functionality of the resolution function, this is done when the debugging tools can distinguish between UDN and UDRN by declaring the resolution function as a variable of the UDRN as illustrated in Figure 4.
- Have a strong builder expression that can construct complex functions equivalent to the functionality of the resolution function because this helps in comparing the outputs from the resolution functions to those generated from the builder expression as shown in Figure 5.

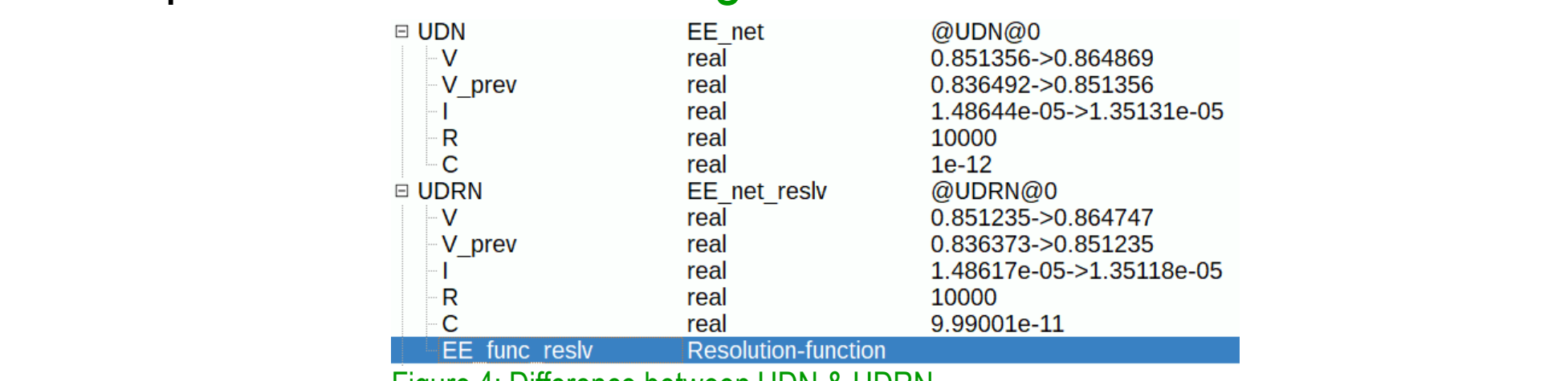


Figure 4: Difference between UDN & UDRN

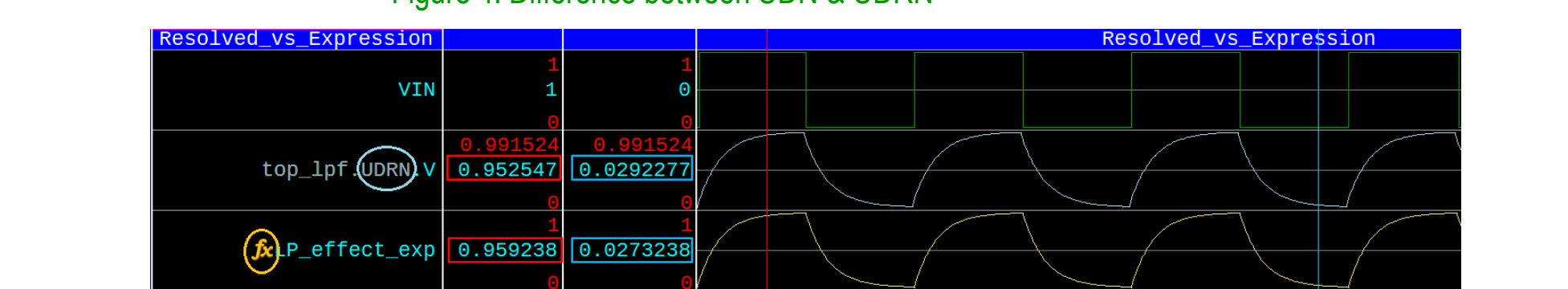


Figure 5: Values of LP filtering effect from UDRN and created expression

Boundary Elements (BEs)

Most simulators support the automatic insertion of BEs by providing the MS-Net hierarchical path. The inserted BE can be defined as a 1-bit ADC (in the case of R2L) or as a 1-bit DAC (in the case of L2R) and it is expected in the future that EDA tools will insert n-bit ADC/DAC automatically. The n-bit generic ADC/DAC, generic meaning without a specific topology to ADC/DACs, can be supported by the following equation

$$\text{For } n\text{-bit ADC: } L(\text{output}_{logic}) = \frac{R(\text{input}_{real})}{\text{delta}}, \quad \text{For } n\text{-bit DAC: } L(\text{output}_{logic}) = R(\text{input}_{real}) * \text{delta}$$

where L: Logic, R: Real, delta = $\frac{v_{ref}}{2^n}$, v_{ref} : supply value, 2^n : number levels of conversion, n: define resolution

The SystemVerilog code that supports an n-bit ADC/DAC can be shown in the following table

n-bit_ADC.sv	n-bit_DAC.sv
<pre>// n to define resolution (accuracy) // number of levels = 2**n // delta = (high supply voltage) / (number of levels) module R2L #(parameter n = 3) (input real R, output wire [0:(n-1)] L); parameter real vsup = 2.5; parameter real vsuplow = 0; parameter real nlevels = 2**n; parameter real delta = vsup / nlevels; reg [0:n-1] R_conv; always @(R) begin if (R == 'wrealZState) R_conv = 'Z; else if (R >= vsup) R_conv = '1; else if (R == vsuplow) R_conv = '0; else if ((vsuplow < R) && (R < vsup)) R_conv = R / delta; else R_conv = 'X; end assign L = R_conv; endmodule</pre>	<pre>// n to define resolution (accuracy) // number of levels = 2**n // delta = (high supply voltage) / (number of levels) module L2R #(parameter n = 3) (input wire [0:(n-1)] L, output real R); parameter real vsup = 2.5; parameter real vsuplow = 0; parameter real nlevels = 2**n; parameter real delta = vsup / nlevels; reg L_conv; always @(L) begin if (L == 'Z') L_conv = 'wrealZState; else if (L == '1') L_conv = vsup; else if (L == '0') L_conv = vsuplow; else if ((0 < L) && (L < '1')) L_conv = L * delta; else L_conv = 'wrealXState; end assign R = L_conv; endmodule</pre>

Debugging BEs

- The tool should define it as a separate instance. This helps to know how many BEs are inserted, where they are inserted and what type of the BE is inserted (R2L, L2R) as shown in Figure 6.
- The BE parameters must be well understood because the designer can change the default values of the BE inserted through configurable files and these values will be propagated through all the design. The highest and the lowest BE parameters values are easily visualized but the values between need smart schematic tools to simply give hints when the 'x' propagates as shown in Figure 7.
- Adding the BE input/output to windows like wave window or smart window for debugging event-driven orders will be very helpful as there are a lot of real values changed to logic '1', logic '0' and some can be changed to 'x' as shown in Figure 8.

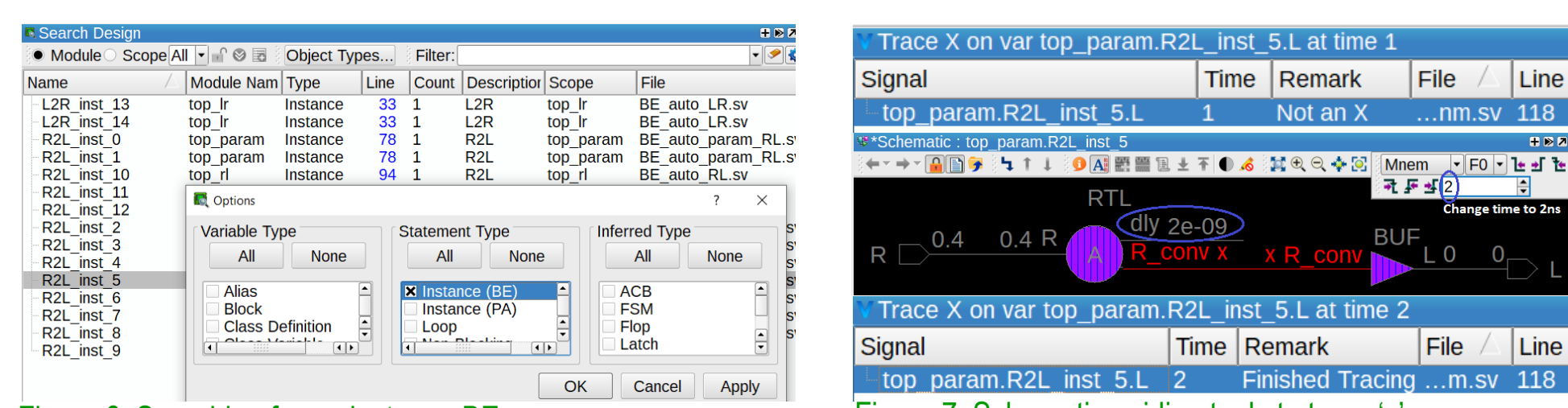


Figure 6: Searching for an instance BE

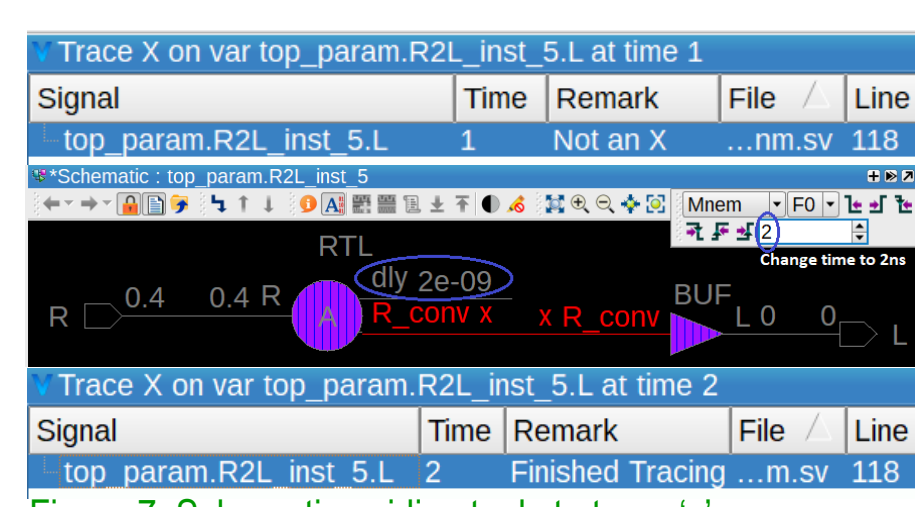


Figure 7: Schematic guiding tools to trace 'x'

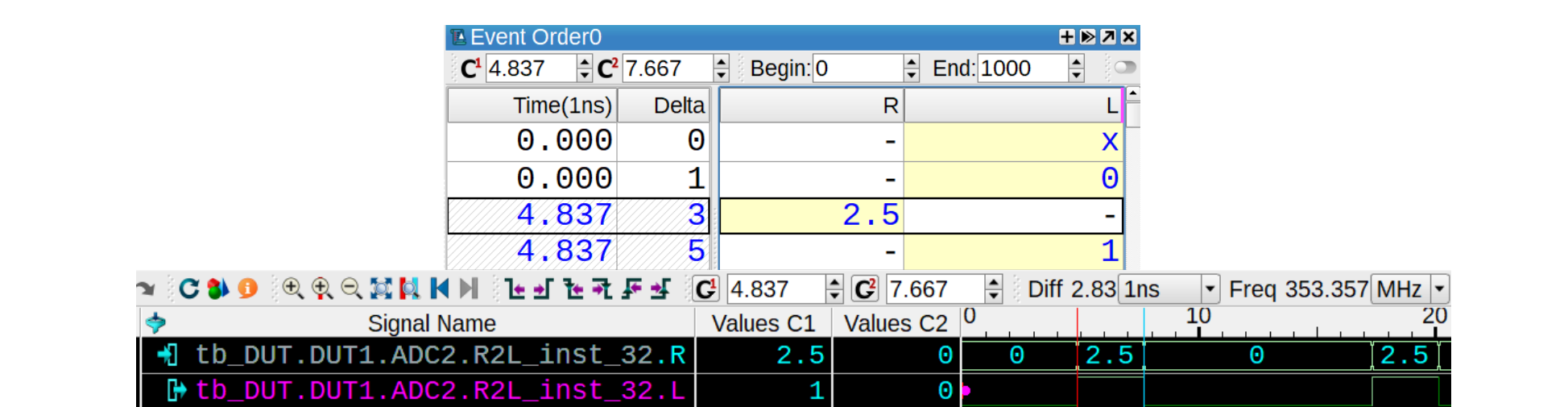


Figure 8: The event order for a 'real' variable

Interconnects

Some devices are structurally wire-based, or the extracted netlist connections of a device are wire-based. If the system is of real datatype, then there will be incompatibility errors during the simulation process. The solution could be:

- Insert two BEs, one R2L and one L2R, so that the wire is between the two inserted BEs (real -- R2L -- wire -- L2R -- real). Only two real values for the highest and lowest data will be received.
- Include n-bit ADC and n-bit DAC. This solution will have information loss according to the number of levels of conversion. It is a hard solution if the tool does not support the automatic insertion of n-bit ADC/DAC and will also change the design hierarchy.
- Convert these wires to interconnect. Interconnect can hold any value according to the type of data connected to it. Therefore, it is the best solution as shown in Figure 9.

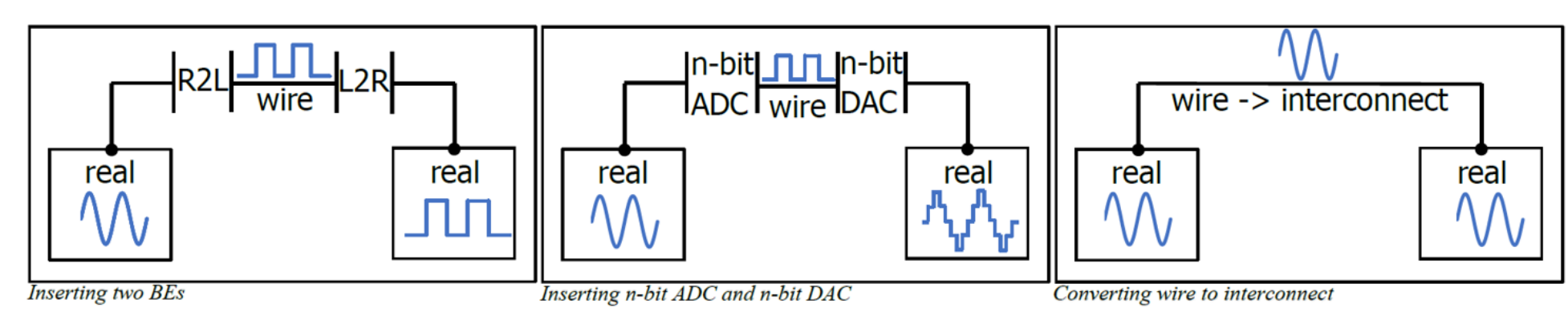


Figure 9: Wire to Interconnect

Debugging Interconnects

- Differentiate between interconnects implicitly defined by the tool and those explicitly defined by the user as in Figure 10.
- Highlight the data type driven by the interconnect, the red box in Figure 10 shows the data type that will be driven by the interconnect between brackets '()'. Show the drivers/receivers of interconnect. Notice that this interconnect connects UDRN because the datatype of the port has a resolution function as shown in Figure 11.

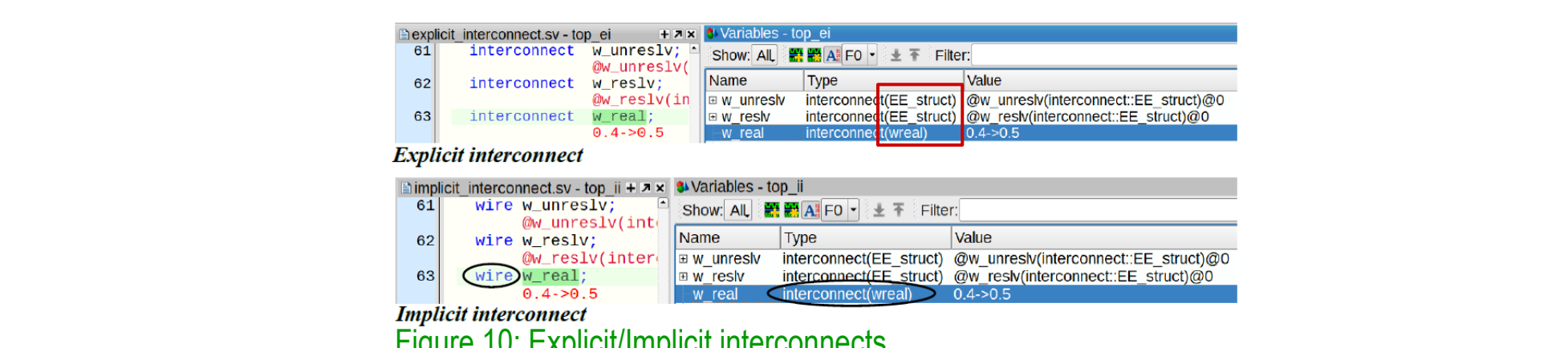


Figure 10: Explicit/Implicit interconnects

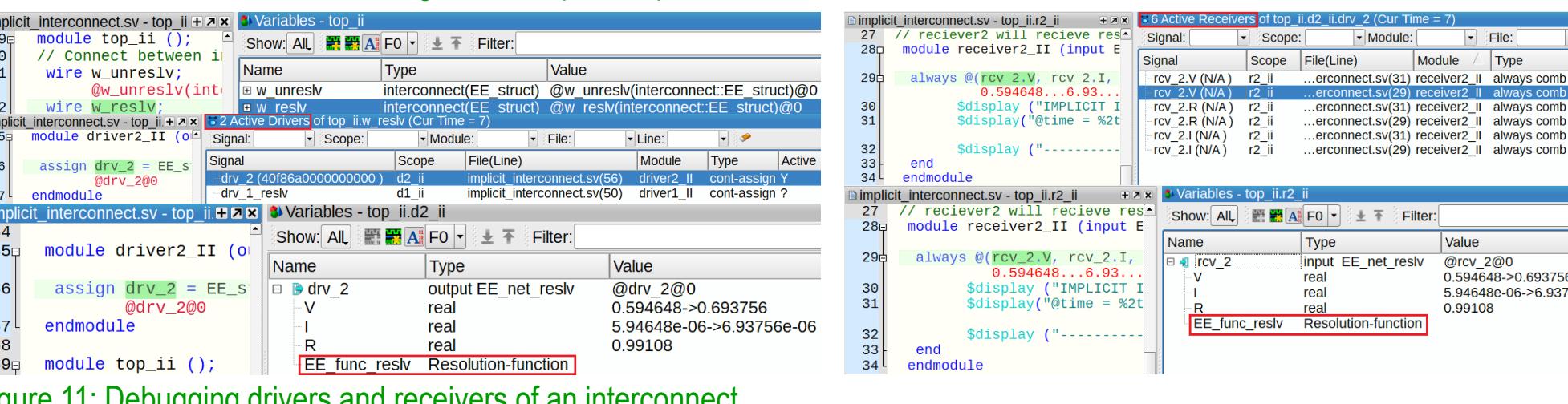


Figure 11: Debugging drivers and receivers of an interconnect

DUT (Generator)

The function generator is used to generate electrical waves such as sine, square, sawtooth, and triangular waves. These waves can be modeled according to the following equations. Any of these waves will be connected to another analog block, for that reason considering its loading effect could be important.

$$\text{sine}_{wave} = \text{offset} + \text{amp} * \sin(2 * \pi * \text{freq} * \text{time} * \text{unit}_{time})$$

$$\text{square}_{wave} = \text{offset} + \text{amp} * \text{sgn}(\sin(2 * \pi * \text{time} * \text{unit}_{time}))$$

$$\text{sawtooth}_{wave} = \text{offset} + ((2 * \text{amp}) / \pi) * \text{Satan}(1 / \text{Satan}(\pi * \text{freq} * \text{time} * \text{unit}_{time}))$$

$$\text{triangular}_{wave} = \text{offset} + ((2 * \text{amp}) / \pi) * \text{Sasin}(1 / \text{Sasin}(\pi * \text{freq} * \text{time} * \text{unit}_{time}))$$

As shown in Figure 12, the tool can provide information about frequency, max/min amplitude, and the offset of the wave. The random Generator can be useful for modeling the noise input wave or adding an amount of noise to the input wave.

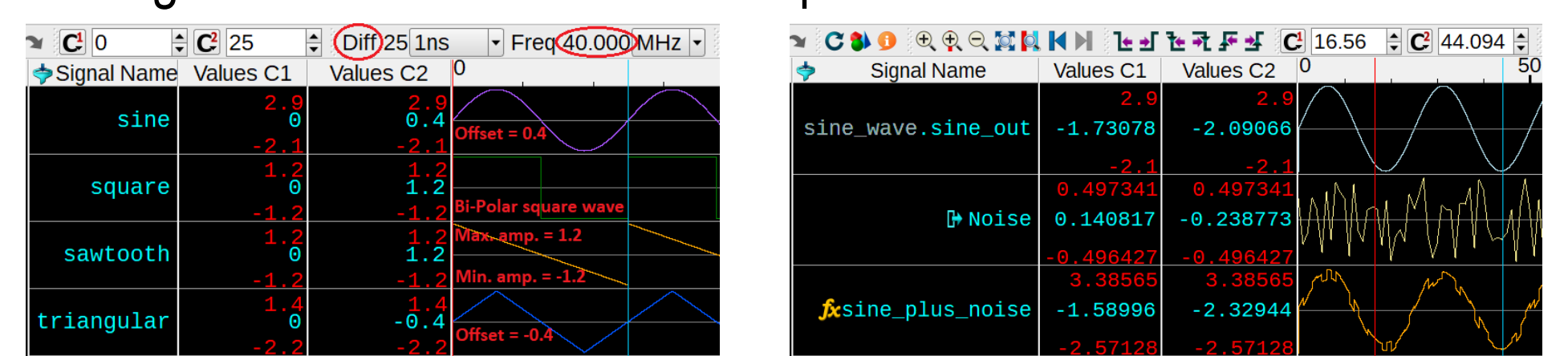


Figure 12: Waves and getting info from their waveforms

DUT (ADC/DACs)

The DUT in Figure 13 has the following devices: two Generators, two ADCs of 4-bit FLASH_ADC, Logical Unit (LU), Arithmetic Unit (AU), one DAC of 4-bit R_STRING DAC and 4-bit generic DAC.

- Wave1 and wave2 are driven by resolved net-types to model the load effect at the analog part, and this loading can reduce the value of the analog voltage that will be driven by ADC.
- Inside the FLASH_ADC there are BEs inserted of R2L type, to convert the real output voltage value of the comparator to the digital input logic value of the encoder. The ADC sub-blocks are structurally wire-based connections, so a wire to interconnect is needed to receive the desired real data between sub-blocks.
- The outputs of the two ADCs will go through the Logical Unit (LU) and the Arithmetic Unit (AU) which are purely digital devices. Then, the LU output will go through the R_STRING_DAC and the DAC's output is a resolved net. Inside the DAC there are BEs inserted of L2R type. The DAC sub-blocks are structurally wire-based connections, so a wire to interconnect is now required. The AU output will go through the n-bit DAC acts as a generic DAC and its output is also resolved net.

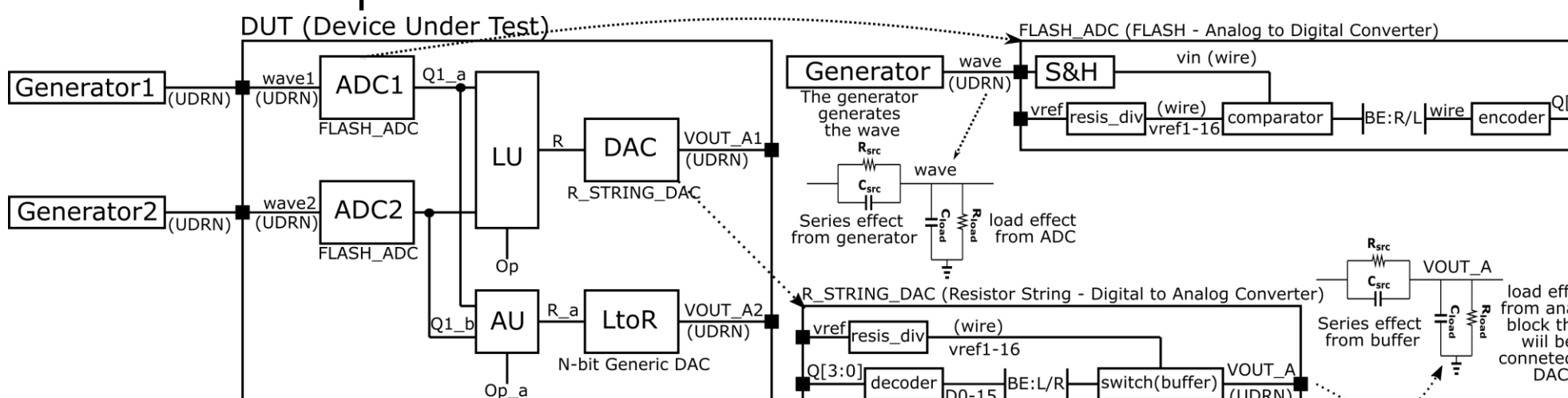


Figure 13: Analog-Mixed Signal DUT, the structure of FLASH_ADC & R_STRING_DAC

DUT (LDOs) / (PhotoDiodes)

Figure 14: The concept of LDO (Low Drop-Out voltage) can be simply modeled as a resistive voltage divide. The LDO reduces the value of the supply battery to the desired analog system supply voltage. It can be modeled with UDRN.

Figure 15: PhotoDiode (PD) can be modeled as a current source with approximate infinity resistance (rsh) and small capacitor due to the effect of the materials (cs). The photodiode is then connected to a trans-impedance amplifier to convert current into voltage. The trans-impedance amplifier has an impedance effect of (cfl/rf).

```
module beh_pd (vout, vin);
    output vout; input vin;
    real vout_prev, real vin_prev;

    // Parameters of photodiode
    parameter real id = 50E-6; // series capacitance
    parameter real rs = 1E9; // shunt resistance

    // Parameters of feedback
    parameter real rf = 20E3; // feedback resistance
    parameter real cf = 10E-12; // feedback capacitance

    // photodiode
    // parameter real TS = 1;
    // parameter real TU = 1E-9;
    // real dt = TS * TU;

    // Constants
    real A, B, C, D;
    always @(vin, sampling_clock) begin
        A = 1/rf;
        B = 1/rsh;
        C = cfl;
        D = cs/dt;

        vin_prev = vin;
        vout_prev = vout;
        vout = ((A+C)*id + (B+D)*vout_prev + (C+D)*vout_prev) / (A+B+C+D);
    end
endmodule
```

Figure 14: LDO

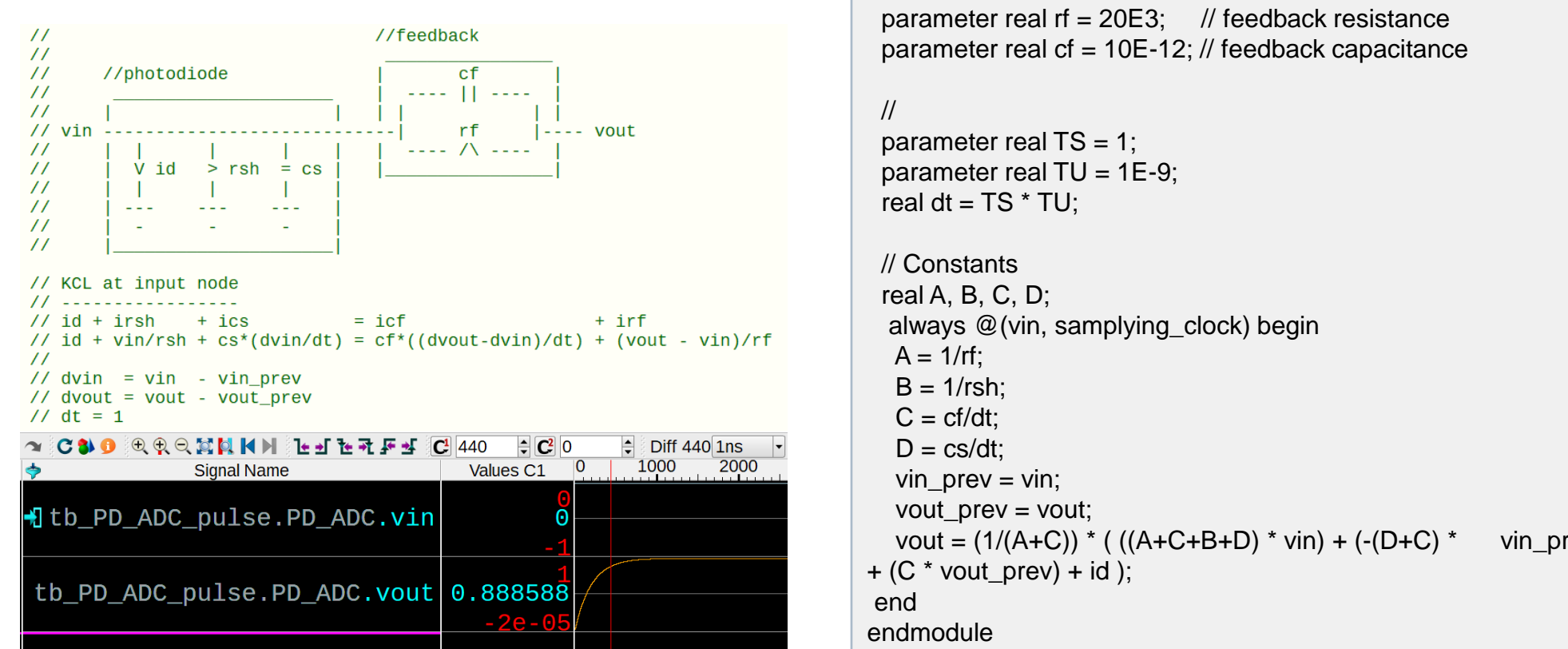


Figure 15: PhotoDiode and its SystemVerilog code.

Conclusion

A lot of analog devices can be modeled using SV-RNM and in the future much of the technical thinking will be towards modeling analog complex devices in the digital environment and will be reflected in the EDA tools from simulation, debugging, and verification of such complex devices. Future work will be on how to verify these devices from UVM-based verification, assertions, and functional coverage.